

# Revisit TP1a EH and VEC based on New Test Method in IEEE 802.3ck D1p4

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For IEEE 802.3ck Ad-Hoc

# Supporters

# Outlines

- Background
- Channel & Analysis
- Impact from New Test Method in D1p4
- TP1a vs Whole-Link Correlation
- Summary & Proposals

# Background

- New test method of C2M TP1a EH/VEC had been adopted in 802.3ck D1p4
  - Proposed in [healey 3ck 02 1020](#)
  - EH/VEC specs in D1p4 are not valid any more
- Run COM analysis based on new method in D1p4 to derive new EH/VEC specs
  - Adopt similar analysis as [wu 3ck 01a 1119](#)
- Proposals for Table 120G-1
  - VEC = 12 dB for TP1a
  - EH = 8 mV for TP1a
  - M1 (samples\_for\_C2M) = 100

# Channel and Analysis

- Channel (crosstalk included) and reference receiver
  - Whole-link & TP1a analysis for total [nineteen IEEE C2M host-to-module channels](#)
    - Sweep host package trace length, z\_p1(TX)
      - z\_p1(TX) = [5:0.5:10 11:1:20 22:2:36]
    - Total 19 \* 29 = 551 CH+PKG test cases

- COM parameter settings [details in appendix]

- COM 3.1
- Whole link: TX Device/PKG + H2M Channels + RX PKG/Device

c_d	[1.2e-4 0.85e-4]	nF	[TX RX]
L_s	[0.12 0.12]	nH	[TX RX]
C_b	[0.3e-4 0.3e-4]	nF	[TX RX]
z_p select	[ 1 2 ]		[test cases to run]
z_p (TX)	[xx ; 1.8 1.8]	mm	[test cases]
z_p (NEXT)	[ 2 8 ; 0 0 ]	mm	[test cases]
z_p (FEXT)	[xx ; 1.8 1.8]	mm	[test cases]
z_p (RX)	[ 2 8 ; 0 0 ]	mm	[test cases]
C_p	[0.87e-4 0.65e-4]	nF	[TX RX]

- TP1a: TX Device/PKG + H2M Channels
  - Set 'zero' to related RX PKG & on-die settings

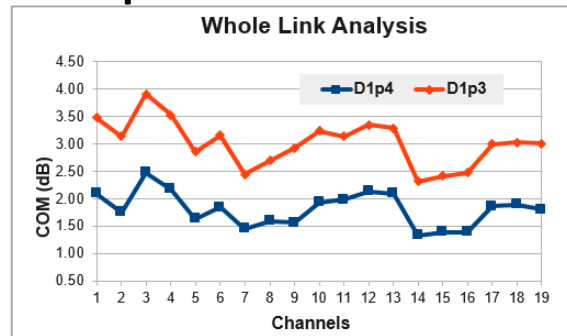
# Impacts to COM, EH & VEC from New Test Method Adopted by D1p4 – D1p3 vs. D1p4

- Considerations of the following parameter changes from D1p3 to D1p4
  - EH/VEC methodology:  $T_O = 25 \rightarrow 50$  mUI
  - New parameters: `samples_for_C2M` (Samples/UI for C2M) = 100
- Observations
  - EH & VEC does degrade based on new method
  - EH & VEC values are sensitive to 'samples\_for\_C2M', shall consider values larger than 32

# Whole Link Analysis – COM Impact

		COM (dB)		D1p4	D1p3
lim_3ck_01a_0319	lim_3ck_01_0319_c2m.zip	Tx7_L10	112G_16dB_(QSFPDD+module card)_TX7_L10	2.09	3.48
		Tx7_L23	112G_16dB_(QSFPDD+module card)_TX7_L23	1.75	3.13
		Tx3_L10	112G_16dB_(QSFPDD+module card)_TX3_L10	2.47	3.90
		Tx3_L23	112G_16dB_(QSFPDD+module card)_TX3_L23	2.17	3.52
		Tx7_Asic	112G_16dB_(QSFPDD+module card)_TX7_Asic	1.63	2.85
		Tx3_Asic	112G_16dB_(QSFPDD+module card)_TX3_Asic	1.85	3.15
lim_3ck_adhoc_01	073119_lim_3ck_adhoc_02_073119.zip	Ch5a_2"	Channel5a_Smaller_Pad_2inch_trace	1.45	2.44
		Ch5b_3"	Channel5b_Smaller_Pad_3inch_trace	1.59	2.69
		Ch5c_4"	Channel5c_Smaller_Pad_4inch_trace	1.57	2.92
		Ch5d_9"	Channel5d_Smaller_Pad_9inch_trace	1.93	3.24
akinwale_3ck_adhoc_01a_08282019	akinwale_3ck_C2M_channels_TP0a_100ohms_08222019.zip	2"100Ohm	C2M_2p0in_100Ohm_thru1.s4p	1.99	3.14
		3"100Ohm	C2M_3p0in_100Ohm_thru1.s4p	2.13	3.34
		4"100Ohm	C2M_4p0in_100Ohm_thru1.s4p	2.09	3.28
		2"850hm	C2M_2p0in_850hm_thru1.s4p	1.33	2.31
		3"850hm	C2M_3p0in_850hm_thru1.s4p	1.39	2.41
		4"850hm	C2M_4p0in_850hm_thru1.s4p	1.39	2.47
		2"950hm	C2M_2p0in_950hm_thru1.s4p	1.86	2.99
		3"950hm	C2M_3p0in_950hm_thru1.s4p	1.89	3.03
4"950hm	C2M_4p0in_950hm_thru1.s4p	1.80	3.00		
		AVG Diff (D1p3 as basis)		-1.21	

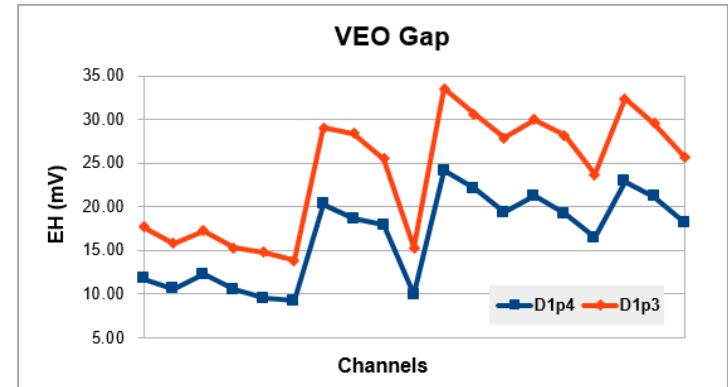
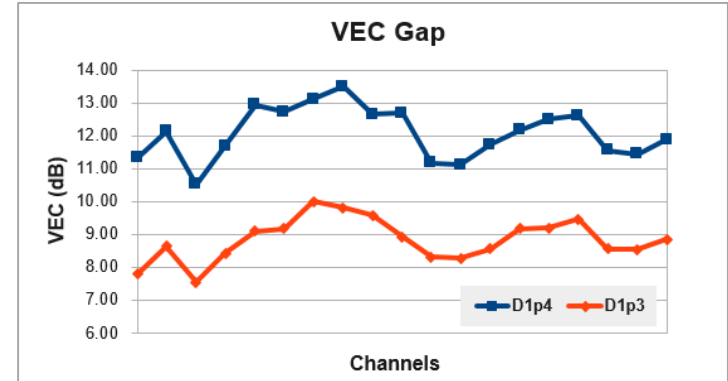
Modified COM threshold = 3 – 1.2 = 1.8dB



- Since we had considered more impairments to derive COM, EH & VEC,
  - Set 3 dB as COM threshold is no longer valid
  - Take into account of COM impact from new method in D1p4, COM threshold shall be set as **1.8** dB for the following analysis

# TP1a Analysis – Impact to VEC & VEO (EH)

				VEC (dB)		EH (mv)	
				D1p4	D1p3	D1p4	D1p3
lim_3ck_01a_0319	lim_3ck_01_0319_c2m.zip	Tx7_L10	112G_16dB_(QSFPPD+module card)_TX7_L10	11.32	7.79	11.76	17.65
		Tx7_L23	112G_16dB_(QSFPPD+module card)_TX7_L23	12.13	8.64	10.56	15.78
		Tx3_L10	112G_16dB_(QSFPPD+module card)_TX3_L10	10.51	7.54	12.24	17.23
		Tx3_L23	112G_16dB_(QSFPPD+module card)_TX3_L23	11.69	8.42	10.49	15.30
		Tx7_Asic	112G_16dB_(QSFPPD+module card)_TX7_Asic	12.93	9.10	9.51	14.78
		Tx3_Asic	112G_16dB_(QSFPPD+module card)_TX3_Asic	12.73	9.18	9.20	13.85
lim_3ck_adhoc_01_1_	073119_lim_3ck_adhoc_02_073119.zip	Ch5a_2"	Channel5a_Smaller_Pad_2inch_trace	13.12	10.00	20.30	29.06
		Ch5b_3"	Channel5b_Smaller_Pad_3inch_trace	13.48	9.81	18.60	28.40
		Ch5c_4"	Channel5c_Smaller_Pad_4inch_trace	12.64	9.58	17.91	25.47
		Ch5d_9"	Channel5d_Smaller_Pad_9inch_trace	12.69	8.92	9.93	15.32
akinwale_3ck_adhoc_01a_08282019	akinwale_3ck_C2M_channels_TP0a_100ohms_08222019.zip	2"100Ohm	C2M_2p0in_100Ohm_thru1.s4p	11.17	8.31	24.09	33.49
		3"100Ohm	C2M_3p0in_100Ohm_thru1.s4p	11.12	8.27	22.07	30.62
		4"100Ohm	C2M_4p0in_100Ohm_thru1.s4p	11.73	8.57	19.35	27.86
		2"850hm	C2M_2p0in_850hm_thru1.s4p	12.17	9.17	21.21	29.96
		3"850hm	C2M_3p0in_850hm_thru1.s4p	12.50	9.19	19.22	28.14
		4"850hm	C2M_4p0in_850hm_thru1.s4p	12.60	9.46	16.48	23.66
		2"950hm	C2M_2p0in_950hm_thru1.s4p	11.55	8.56	22.91	32.33
		3"950hm	C2M_3p0in_950hm_thru1.s4p	11.44	8.54	21.14	29.54
4"950hm	C2M_4p0in_950hm_thru1.s4p	11.88	8.85	18.15	25.72		
Diff (D1p3 as basis)				3.24	-7.32		





# Time Interval and Samples for C2M

- Time interval for eye analysis

- D1p3: 25 mUI
- D1p4: 50 mUI

- Samples/UI for C2M (take it as M1)

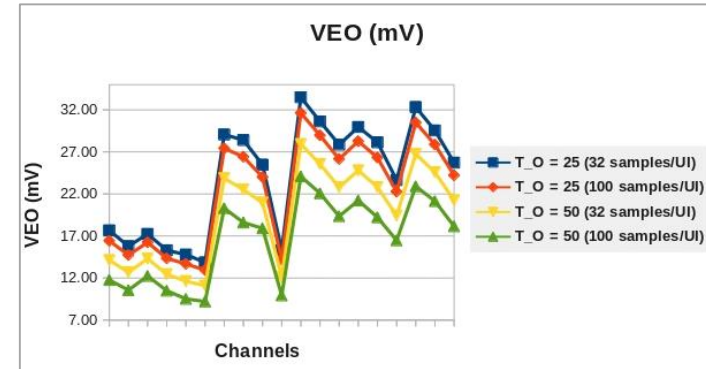
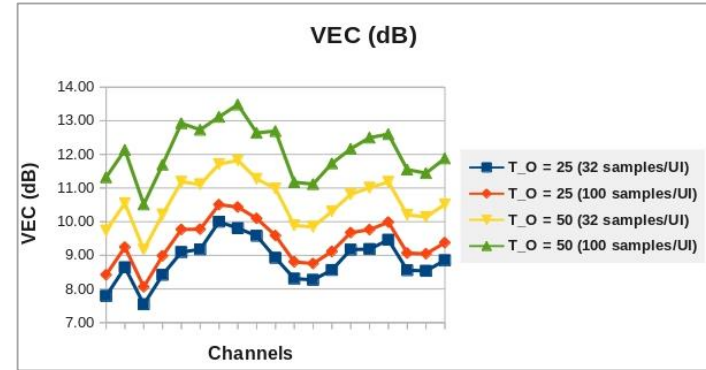
- M1 = [32 100]
- VEC & EH difference is **1.46 dB** & **-2.97 mV** among M1 = 32 & 100 under T\_O = 50 mUI

- We need to specify M1 clearly

- Propose to set M1 = 100

T_O (mUI)	25	25	50	50
Samples/UI	32	100	32	100
112G_16dB (QSFPDD+module card) TX7_L10	7.79	8.42	9.73	11.32
112G_16dB (QSFPDD+module card) TX7_L23	8.64	9.24	10.55	12.13
112G_16dB (QSFPDD+module card) TX3_L10	7.54	8.06	9.17	10.51
112G_16dB (QSFPDD+module card) TX3_L23	8.42	8.98	10.21	11.69
112G_16dB (QSFPDD+module card) TX7_Asic	9.10	9.77	11.18	12.93
112G_16dB (QSFPDD+module card) TX3_Asic	9.18	9.78	11.11	12.73
Channel5a Smaller Pad_2inch trace	10.00	10.51	11.71	13.12
Channel5b Smaller Pad_3inch trace	9.81	10.43	11.82	13.48
Channel5c Smaller Pad_4inch trace	9.58	10.10	11.27	12.64
Channel5d Smaller Pad_9inch trace	8.92	9.59	10.98	12.69
C2M_2p0in_100Ohm_thru1.s4p	8.31	8.81	9.89	11.17
C2M_3p0in_100Ohm_thru1.s4p	8.27	8.76	9.85	11.12
C2M_4p0in_100Ohm_thru1.s4p	8.57	9.12	10.31	11.73
C2M_2p0in_85Ohm_thru1.s4p	9.17	9.68	10.81	12.17
C2M_3p0in_85Ohm_thru1.s4p	9.19	9.76	11.01	12.50
C2M_4p0in_85Ohm_thru1.s4p	9.46	9.99	11.18	12.60
C2M_2p0in_95Ohm_thru1.s4p	8.56	9.07	10.20	11.55
C2M_3p0in_95Ohm_thru1.s4p	8.54	9.05	10.14	11.44
C2M_4p0in_95Ohm_thru1.s4p	8.85	9.37	10.52	11.88
VEC Avg	8.84	9.39	10.61	12.07

T_O (mUI)	25	25	50	50
Samples/UI	32	100	32	100
112G_16dB (QSFPDD+module card) TX7_L10	17.65	16.42	14.12	11.76
112G_16dB (QSFPDD+module card) TX7_L23	15.78	14.73	12.67	10.56
112G_16dB (QSFPDD+module card) TX3_L10	17.23	16.24	14.30	12.24
112G_16dB (QSFPDD+module card) TX3_L23	15.30	14.33	12.44	10.49
112G_16dB (QSFPDD+module card) TX7_Asic	14.78	13.68	11.62	9.51
112G_16dB (QSFPDD+module card) TX3_Asic	13.85	12.93	11.09	9.20
Channel5a Smaller Pad_2inch trace	29.06	27.42	23.87	20.30
Channel5b Smaller Pad_3inch trace	28.40	26.42	22.51	18.60
Channel5c Smaller Pad_4inch trace	25.47	24.00	20.97	17.91
Channel5d Smaller Pad_9inch trace	15.32	14.19	12.09	9.93
C2M_2p0in_100Ohm_thru1.s4p	33.49	31.63	27.92	24.09
C2M_3p0in_100Ohm_thru1.s4p	30.62	28.96	25.55	22.07
C2M_4p0in_100Ohm_thru1.s4p	27.86	26.14	22.79	19.35
C2M_2p0in_85Ohm_thru1.s4p	29.96	28.26	24.79	21.21
C2M_3p0in_85Ohm_thru1.s4p	28.14	26.33	22.81	19.22
C2M_4p0in_85Ohm_thru1.s4p	23.66	22.26	19.40	16.48
C2M_2p0in_95Ohm_thru1.s4p	32.33	30.49	26.75	22.91
C2M_3p0in_95Ohm_thru1.s4p	29.54	27.87	24.57	21.14
C2M_4p0in_95Ohm_thru1.s4p	25.72	24.22	21.24	18.15
VEO Avg	23.90	22.45	19.55	16.58



# Summary of Impacts from New Test Method

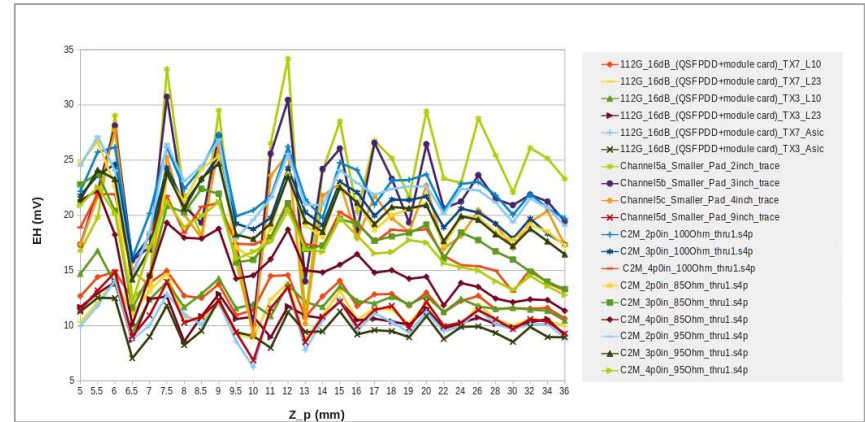
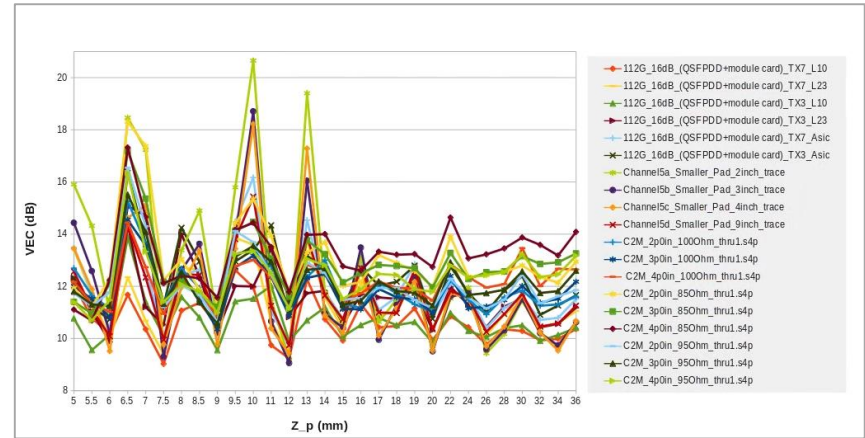
- Difference of COM, VEC, & EH (D1p4 – D1p3)
- Difference of VEC & EH by different Samples/UI for C2M ( 100 – 32 )

Item	Difference
COM	-1.21 dB
VEC	3.24 dB
EH	-7.32 mV

Item	Difference
VEC	1.46 dB
EH	-2.97 mV

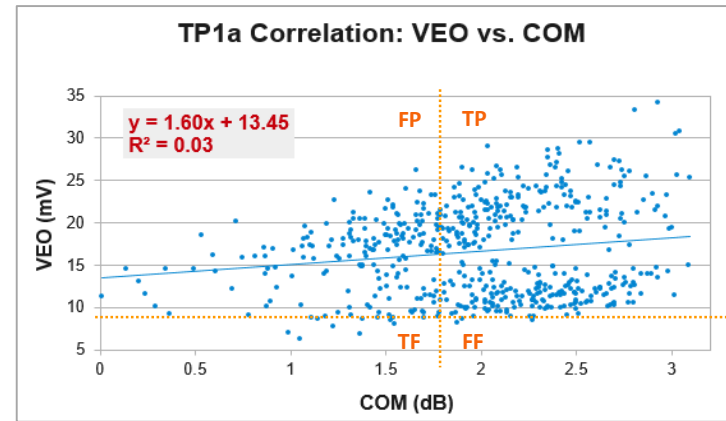
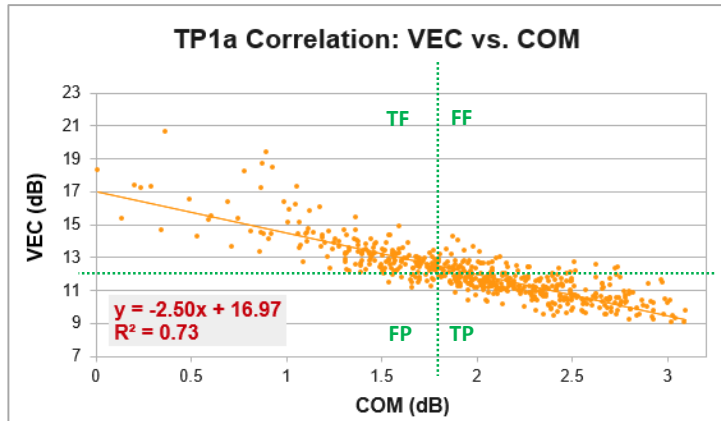
# TP1a Analysis Observation

- Based on M1 = 100
- VEC/EH performance variations are higher in short channels, comparing to long ones
- EH values of short and long channels are separated into two obvious groups
  - We need to set EH (min) spec carefully to avoid falsely failing good short channels
- Solutions: do the correlation to COM



# EH/VEC vs. COM Correlation – Check Correlation

- Take COM  $\geq 1.8$  dB as pass indicator
- Correlation of COM and VEC/VEO
  - VEC (dB) is kind of correlated to COM in whole link analysis, while EH (mV) doesn't
  - VEC:  $R^2 = 0.73$
  - VEO (EH):  $R^2 = 0.03$
- Which is better indicators? VEC vs. EH
  - VEC is a very good indicator for DUT performance
  - EH is NOT strongly correlated to COM, especially for short channels
- Too high of EH threshold risks over-kill good DUT

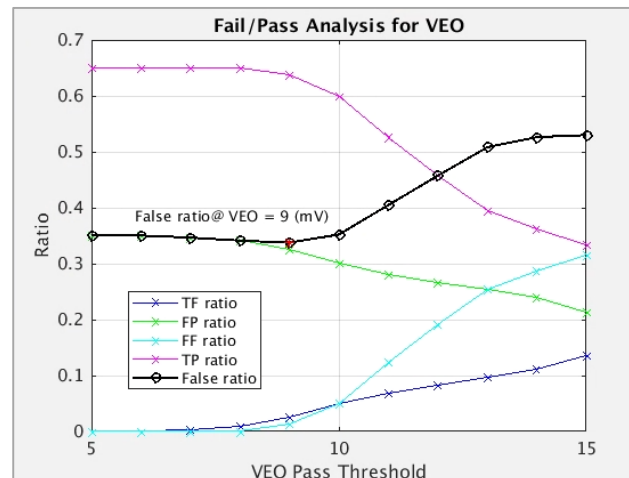
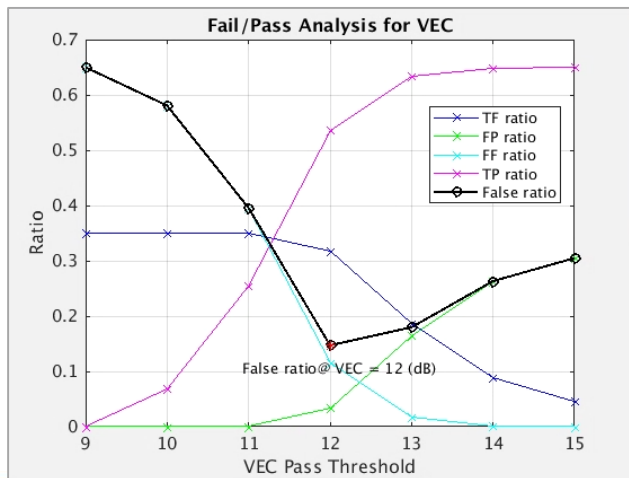


# Pass/Fail Analysis – Take False Ratio as Criterion

- Definitions of True/False-Pass/Fail

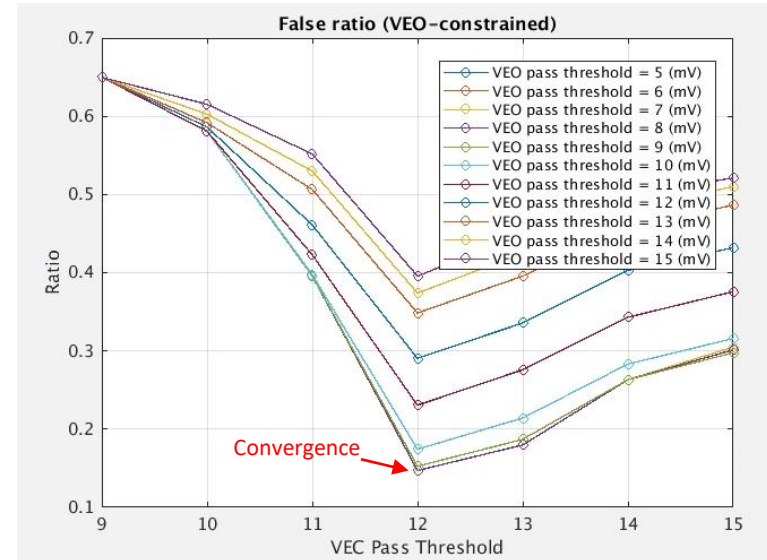
	VEC $\leq$ pass threshold (VEO $\geq$ pass threshold)	VEC $>$ pass threshold (VEO $<$ pass threshold)
COM $\geq$ 1.8 dB	True-Pass (TP)	False-Fail (FF)
COM $<$ 1.8 dB	False-Pass (FP)	True-Fail (TF)

- Take COM  $\geq$  1.8 dB as pass indicator
- Find VEC & EH thresholds to minimize False ratio = FP + FF ratios
  - VEC = 12 dB with 14.70% False ratio
  - EH = 9 mV with 33.76% False ratio  $\rightarrow$  quite high, not a good indicator for performance
- Next: Combine two of them



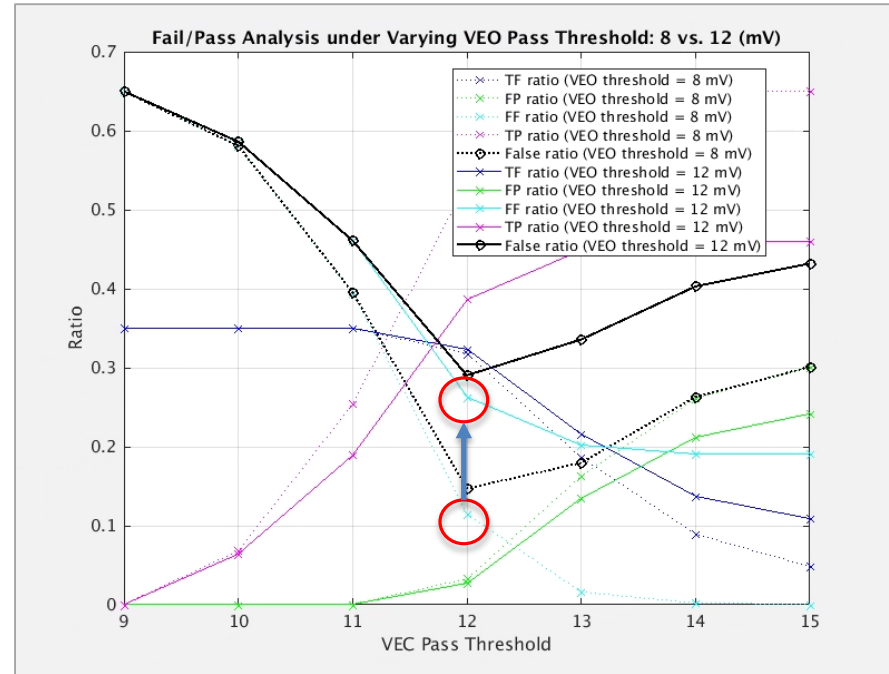
# Joint Correlation of VEC/VEO

- **VEO-constrained** VEC is adopted to conjunctively combine separate pass/fail decisions
  - The procedure adopted in D1p4
  - Filtering samples that didn't meet VEO requirement → [5:15] mV
- Optimal false ratio converges at (with False ratio = 14.7%)
  - VEC pass threshold = 12 dB
  - VEO pass threshold = 8 mV
- Q: is EH (min) = 8 mV too small the value?



# Increasing EH (min) doesn't Help, but Hurt

- Increasing EH (min) from 8 mV to 12 mV, for example
  - Actually over-kill good DUT (~15% False-Fail ratio increase)
  - No benefits to drop false-passed bad DUT (nearly the same False-Pass ratio)
- The major indicator shall be VEC (max) & keep EH (min) low enough to avoid over-kill good Host DUT
- Analysis also shows -7.32 mV EH decrease due to new method in D1p4
  - EH (min) = 15 mV as old method



# Summary & Proposals

- New TP1a test method impacts VEC & EH & we need new thresholds in D1p5 to reflect that
  - Impact to VEC & EH = +3.24 dB & -7.32 mV
- Based on COM vs. VEC/EH correlation to derive the following new thresholds for D1p5

Spec	D1p4	D1p5
VEC	9 dB	12 dB
EH	15 mV	8 mV
M1, samples_for_C2M	N/A	100



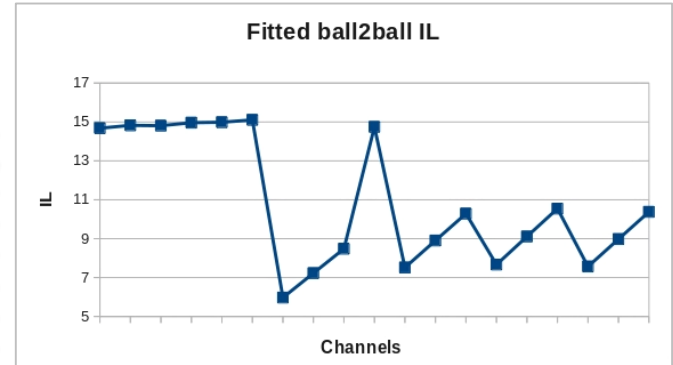
Thank You



# C2M Host-to-Module Channels for Analysis

- Short Channel
- Long Channel

Contribution	Zip files	Channel	SxP Files	
lim_3ck_01a_0319	lim_3ck_01_0319_c2m.zip	Tx7_L10	112G_16dB_(QSPDD+module card)_TX7_L10	●
		Tx7_L23	112G_16dB_(QSPDD+module card)_TX7_L23	●
		Tx3_L10	112G_16dB_(QSPDD+module card)_TX3_L10	●
		Tx3_L23	112G_16dB_(QSPDD+module card)_TX3_L23	●
		Tx7_Asic	112G_16dB_(QSPDD+module card)_TX7_Asic	●
		Tx3_Asic	112G_16dB_(QSPDD+module card)_TX3_Asic	●
lim_3ck_adhoc_01_	073119 lim_3ck_adhoc_02_073119.zip	Ch5a_2"	Channel5a_Smaller_Pad_2inch_trace	●
		Ch5b_3"	Channel5b_Smaller_Pad_3inch_trace	●
		Ch5c_4"	Channel5c_Smaller_Pad_4inch_trace	●
		Ch5d_9"	Channel5d_Smaller_Pad_9inch_trace	●
akinwale_3ck_adhoc_01a_08282019	akinwale_3ck_C2M_channels_TP0a_100ohms_08222019.zip	2"100Ohm	C2M_2p0in_100Ohm_thru1.s4p	●
		3"100Ohm	C2M_3p0in_100Ohm_thru1.s4p	●
		4"100Ohm	C2M_4p0in_100Ohm_thru1.s4p	●
	akinwale_3ck_C2M_channels_TP0a_85ohms_08222019.zip	2"85Ohm	C2M_2p0in_85Ohm_thru1.s4p	●
		3"85Ohm	C2M_3p0in_85Ohm_thru1.s4p	●
		4"85Ohm	C2M_4p0in_85Ohm_thru1.s4p	●
	akinwale_3ck_C2M_channels_TP0a_93Ohms_08222019.zip	2"93Ohm	C2M_2p0in_93Ohm_thru1.s4p	●
		3"93Ohm	C2M_3p0in_93Ohm_thru1.s4p	●
		4"93Ohm	C2M_4p0in_93Ohm_thru1.s4p	●



# COM Settings – Whole Link (for COM Value)

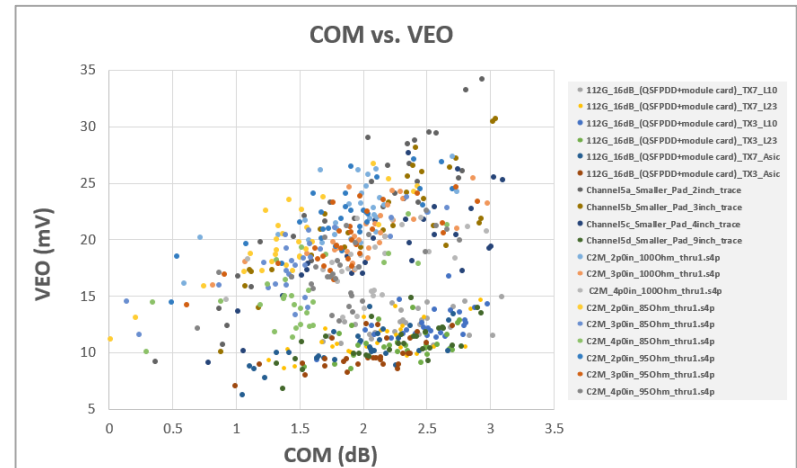
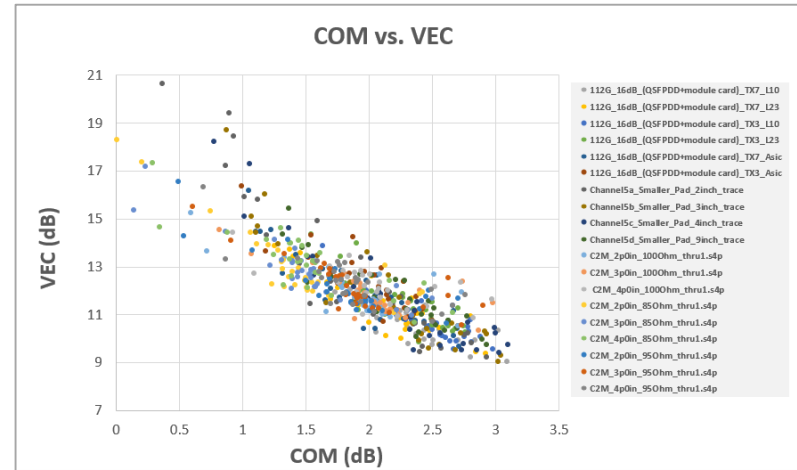
Table 93A-1 parameters				I/O control			Table 93A-3 parameters			Floating Tap Control			
Parameter	Setting	Units	Information	Parameter	Setting	Units	Parameter	Setting	Units	Parameter	Setting	Units	Information
f_b	53.125	GBd		DIAGNOSTICS	1	logical	package_tl_gamma0_a1_a2	[0.0009909 0.0002772]		N_bg	0	012 or 3 groups	
f_min	0.05	GHz		DISPLAY_WINDOW	0	logical	package_tl_tau	6.44E-03	ns/mm	N_bf	3	taps per group	
Delta_f	0.01	nHz		CSV_REPORT	0	logical	package_Z_c	[87.5 87.5 ; 92.5 92.5 ]	Ohm	N_f	40	span for floating taps	
C_d	[1.2e-4 0.85e-4]	nF	[TX RX]	RESULT_DIR	results\100GEL_C2M_host_id.txt		ICN & FOM_ID parameters			bmag	0.2	FE value for floating taps	
L_s	[0.12 0.12]	nH	[TX RX]	SAVE_FIGURES	0	logical	f_v	0.594	*Fb	for TP4-->			
C_b	[0.3e-4 0.3e-4]	nF	[TX RX]	Port Order	[1 3 2 4]		f_n	0.594	GHz	[0.12 0]	nH	[TX RX]	
z_p select	[ 12 ]		(test cases to run)	RUNTAG	C2M_eval		f_2	40	GHz	[0.3e-4 0]	nF	[TX RX]	
z_p (TX)	[12.16 ; 18.18]	mm	[test cases]	COM_CONTRIBUTION	0	logical	A_ft	0.600	v	[ 12.3 ]			(test cases to run)
z_p (NEXT)	[ 2.8 ; 0.0 ]	mm	[test cases]	Local Search	2		A_nt	0.600	v	[ 2.7.8 ]	mm	[test cases]	
z_p (FEXT)	[12.16 ; 18.18]	mm	[test cases]	Operational			Table 92-12 parameters						
z_p (RX)	[ 2.8 ; 0.0 ]	mm	[test cases]	VEC Pass threshold	9	db	board_tl_gamma0_a1_a2	[0.3.8206e-04 3.9509e-05]		board_tl_tau	0.00579	ns/mm	
C_p	[0.87e-4 0.65e-4]	nF	[TX RX]	EH_min	15	mV	board_Z_c	100	Ohm	z_bp (TX)	407	mm	
R_0	50	Ohm		ERL Pass threshold	7.3	dB	z_bp (NEXT)	407	mm	z_bp (FEXT)	407	mm	
R_d	[50 50]	Ohm	[TX RX]	DER_0	0.00001		z_bp (RX)	407	mm	C_0	0	nF	
A_v	0.415	V	vp/vs: 694	T_f	0.0075	ns	C_1	0	nF	Include PCB	0	logical	
A_fe	0.415	V	vp/vs: 694	FORCE_TR	1	5							
A_ne	0.608	V		FMD_type	C2M								
L	4			BREAD_CRUMBS	0	logical							
M	32	Samp/UI		SAVE_CONFIG2MAT	1	logical							
samples_for_C2M	100	Samp/UI		PLOT_CM	0	logical							
T_O	50	mUI		TDR and ERL options									
AC_CM_RMS	0	V	[test cases]	TDR	1	logical							
filter and Eq				ERL	1	logical							
f_r	0.75	'b		ERL_ONLY	0	logical							
c(0)	0.54		min	TR_TDR	0.01	ns							
c(-1)	[-0.2 0.02 0]		[min:step:mas]	N	800								
c(-2)	[0.0 0.02 0.1]		[min:step:mas]	beta_x	0								
c(-3)	[ 0 ]		[min:step:mas]	rho_x	0.618								
c(t)	[-0.10 0.02 0]		[min:step:mas]	fixture ds by time	[ 0 0.2e-9 ]	[port1 port2]							
N_b	4	UI		TDR_V_TXPKG	1								
b_max(1)	0.4		As/dffe1	N_bx	0	UI							
b_max(2..N_b)	[0.15 0.10 0.1]		As/dfe2..N_b	Tukey_Window	1								
b_min(1)	0.1		As/dffe1	Receiver testing									
b_min(2..N_b)	[-0.15 - 0.05 - 0.05]		As/dfe2..N_b	RX_CALIBRATION	0	logical							
g_DC	[-13:1:0]	dB	[min:step:mas]	Sigma BBN step	5.00E-03	V							
f_z	12.58	GHz		Noise, jitter									
f_p1	20	GHz		sigma_RJ	0.01	UI							
f_p2	28	GHz		A_DD	0.02	UI							
g_DC_HP	[-3:0.5:0]	dB	[min:step:mas]	eta_0	4.10E-08	V^2/GHz							
f_HP_P2	1.328125	GHz		SNR_TX	32.5	dB							
G_Qual	[-2 -9 ; 2 -12 ; -4 -12 ; 6 -13]	dB	ranges	R_LM	0.95								
G2_Qual	[0 -1 -2 -3]	dB	ranges										

# COM Settings – TP1a

Table 93A-1 parameters				I/O control			Table 93A-3 parameters			Floating Tap Control			
Parameter	Setting	Units	Information	Parameter	Setting	Units	Parameter	Setting	Units	Parameter	Setting	Units	Information
f_b	53.125	GBd		DIAGNOSTICS	1	logical	package_tl_gamma0_a1_a2	[0 0.0009909 0.0002772]		N_bg	0	0.12 or 3 groups	
f_min	0.05	GHz		DISPLAY_WINDOW	0	logical	package_tl_tau	6.14E-03	ns/mm	N_bf	3	taps per group	
Delta_f	0.01	GHz		RESULT_DIR	results100GEL_C2M_host_1\data		package_Z_c	[87.5 87.5 ; 92.5 92.5 ]	Ohm	N_f	40	span for floating taps	
C_d	[1.2e-4 0]	nF	[TX RX]	SAVE_FIGURES	0	logical	ICN & FOM_ILD parameters			brmag	0.2	FE value for floating taps	
L_s	[0.12 0]	nH	[TX RX]	Port Order	[1 3 2 4]		f_v	0.594	*Fb	for TP4-->			
C_b	[0.3e-4 0]	nF	[TX RX]	RUNTAG	C2M_eval		f_f	0.594	GHz f_r specified in first column	[1.2e-4 0]	nF	[TX RX]	
z_p select	[ 12 ]		[test cases to run]	COM_CONTRIBUTION	0	logical	f_n	0.594	GHz	[0.12 0]	nH	[TX RX]	
z_p (TX)	[12 16; 18 18]	mm	[test cases]	Local Search	2		f_2	40	GHz	[0.3e-4 0]	nF	[TX RX]	
z_p (NEXT)	[ 0 0 ; 0 0 ]	mm	[test cases]	Operational				A_ft	0.600	v	[ 12 3 ]		[test cases to run]
z_p (FEXT)	[12 16; 18 18]	mm	[test cases]	VEC Pass threshold	9	db	A_nt	0.600	v	[ 2 7 8 ]	mm	[test cases]	
z_p (RX)	[ 0 0 ; 0 0 ]	mm	[test cases]	EH_min	15	mV				[ 0 0 0 ]	mm	[test cases]	
C_p	[0.87e-4 0]	nF	[TX RX]	ERL Pass threshold	7.3	dB				[ 2 7 8 ]	mm	[test cases]	
R_0	50	Ohm		DER_0	0.00001					[ 0 0 0 ]	mm	[test cases]	
R_d	[50 50]	Ohm	[TX RX]	T_r	0.0075	ns				[ 0 0 7 e-4 ]	nF	[TX RX]	
A_v	0.415	V	vpl/vf: 694	FORCE_TR	1	5							
A_fe	0.415	V	vpl/vf: 694	PMD_type	C2M								
A_ne	0.608	V		BREAD_CRUMBS	0	logical							
L	4			SAVE_CONFIG2MAT	1	logical							
M	32	Samp/UI		PLOT_CM	0	logical							
samples_for_C2M	100	Samp/UI		TDR and ERL options									
T_0	50	mUI		TDR	1	logical							
AC_CM_RMS	0	V	[test cases]	ERL	1	logical							
filter and Eq				ERL_ONLY	0	logical							
f_r	0.75	'yb		TR_TDR	0.01	ns							
cf(0)	0.54		min	N	800								
cf-1)	[-0.2,0.02,0]		[min:step:max]	beta_x	0								
cf-2)	[0.0,0.02,0.1]		[min:step:max]	rho_x	0.618								
cf-3)	[ 0 ]		[min:step:max]	fixtms delay time	[ 0 0.2e-9 ]	[ port: port2 ]							
cf()	[-0.10,0.02,0]		[min:step:max]	TDR_V_TXPKG	1								
N_b	4	UI		N_bw	0	UI							
b_max(1)	0.4	As/dffe1		Tukey_Window	1								
b_max(2..N_b)	[0.15 0.10 0.1]	As/dfez..N_b		Receiver testing									
b_min(1)	0.1	As/dffe1		RX_CALIBRATION	0	logical							
b_min(2..N_b)	[-0.15 - 0.05 - 0.05]	As/dfez..N_b		Sigma BBN step	5.00E-03	V							
g_DC	[-13:1:0]	dB	[min:step:max]	Noise, jitter									
f_z	12.58	GHz		sigma_RJ	0.01	UI							
f_p1	20	GHz		A_DD	0.02	UI							
f_p2	28	GHz		eta_0	4.10E-08	V^2/GHz							
g_DC_HP	[-30.5:0]		[min:step:max]	SNR_TX	32.5	dB							
f_HP_P2	1.378125	GHz		R_LM	0.95								
G_Qual	[-2 -9 ; -2 -12 ; -4 -12 ; 6 -12]	dB	ranges										
G2_Qual	[ 0 -1 -2 -3 ]	dB	ranges										

# TP1a vs. Whole Link Correlation

- VEC (dB) is kind of correlated to COM in whole link analysis, while the correlation among EH (mV) & COM is less significant



# Pass/Fail Analysis – Take False ratio as criterion

- Definition of True/False-Pass/Fail

	VEC $\leq$ pass threshold (VEO $\geq$ pass threshold)	VEC $>$ pass threshold (VEO $<$ pass threshold)
COM $\geq$ 2 dB	True-Pass (TP)	False-Fail (FF)
COM $<$ 2 dB	False-Pass (FP)	True-Fail (TF)

- Take COM  $\geq$  2 dB as pass indicator
- Find VEC & EH thresholds to minimize False ratio = FP + FF ratios
  - VEC = 12 dB with 16.33% False ratio
  - EH = 10 mV with 46.28% False ratio  $\rightarrow$  quite high

